



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

APPLICANT : Paul Hansma et al.

SERIAL NO.: 08/709,349

FILED : 9/6/96

FOR : Atomic Force Microscope  
for Generating a Small Incident Beam

DOCKET NO.: 1279-225XX

) Examiner Unknown

) Art Unit 2516

5/a  
fd  
3-18-98  
RECEIVED

MAR 17 1998

GROUP 2500

AMENDMENT

March 5, 1998  
865 South Figueroa Street #2800  
Los Angeles, California 90017  
(213) 892-9200

Asst. Commissioner for Patents  
Washington, D. C. 20231

Sir:

In response to the Office Action of November 10, 1997, please cancel  
claim 2, amend claims 1, 3, and 10, and add claim 24 as follows:

IN THE CLAIMS:

1.(Amended) In an atomic force microscope including  
at least one cantilever mounted therein and an optical detector, the  
improvement, for generating a small incident beam spot, comprising:  
an optical system including a light source and means for  
producing [a focused] an incident beam, and at least one lens for focusing said  
incident beam; and